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| Notice of References Cited | Application/Control No. 10/614,056 | Applicant(s)/Patent Under Reexamination ANDO, TAKESHI | |
| | Examiner Chuck Huynh | Art Unit 2683 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| | A | US-6,192,115 | 02-2001 | Toy et al. | 379/130 |
| | B | US-6,138,008 | 10-2000 | Dunn et al. | 455/417 |
| | C | US-6,754,490 | 06-2004 | Okoro et al. | 455/432.2 |
| | D | US-5,991,721 | 11-1999 | Asano et al. | 704/257 |
| | E | US-6,615,041 | 09-2003 | Adamany et al. | 455/432.1 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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